

# Combinatorial Screening of Organic Field Effect Transistors

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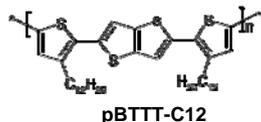
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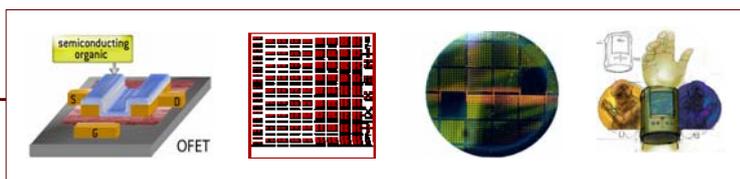
## Motivation

- Organic semiconductors are used in developing applications such as organic light emitting diodes (OLEDs), photovoltaics, radio-frequency identification tags (RFIDs) and organic field effect transistors (OFETs)
- Microstructure of OFET active layer critically affects charge transport and device performance, which varies greatly due to processing conditions (e.g. casting solvent or spin speed)
- Advancing OFET technology requires understanding of the processing, structure and performance, yet current measurement methods used for traditional semiconductors cannot be always be directly transferred, and are stretched to cover a large variable space
- Combinatorial analysis covers a large processing parameter space, is systematic and high-throughput making research more productive and less wasteful

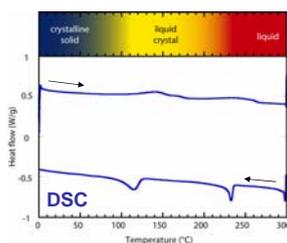
## Objective



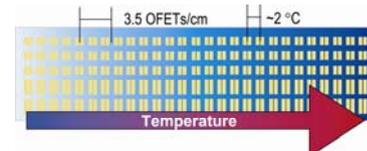
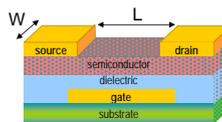
**Goal:** Using a gradient combinatorial approach, study effects of temperature on the microstructure and hole mobility of pBTTT-C<sub>12</sub> thin films



## Approach



- pBTTT-C<sub>12</sub>** is a high performance **solution processible** semiconductor developed by Merck (McCulloch *et al.* *Nature Materials* 5, 243, 2006)
- Saturation hole mobility 0.2 cm<sup>2</sup>/V·s (comparable to a-Si)
- Improved mobility after annealing to liquid crystal phase as mapped by powder differential scanning calorimetry (DSC)



### Thermal Gradient

- pBTTT-C<sub>12</sub> spin coated from warm dichlorobenzene onto OTS-SiO<sub>2</sub>
- Top contact gold S/D electrodes where channel width (W) = 1 or 2 mm and channel length (L) = 80 to 220 μm
- Thermal gradient anneal in nitrogen ΔT ~ 75°C
- Heated for 5 min, cooled to 80 °C (15 min)

## Near Edge X-ray Absorption Fine Structure (NEXAFS) Spectroscopy

### Features:

- High sensitivity to π bonding
- Directly measures molecular orientation
- Depth sensitive
- Collects chemistry and orientation information simultaneously
- Quantification

Resonance Intensity:

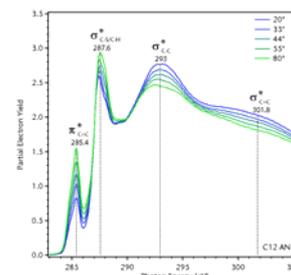
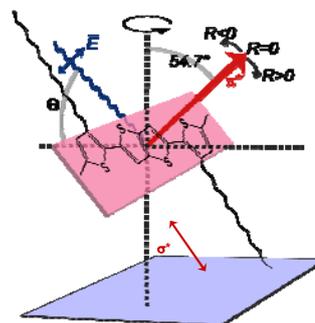
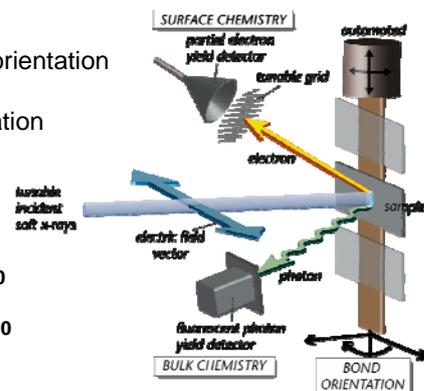
$$I(\theta) = \int PEY(\theta)$$

Edge-On  
R = 0.70

Dichroic Ratio:

$$R = \frac{I(90^\circ) - I(0^\circ)}{I(90^\circ) + I(0^\circ)}$$

Plane-On  
R = -1.00

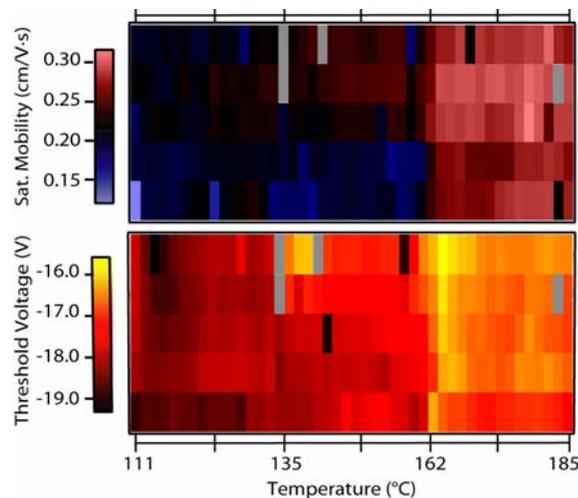
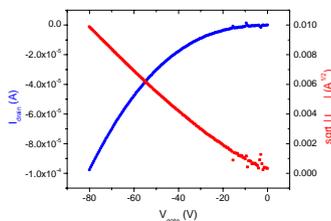


# Highlights

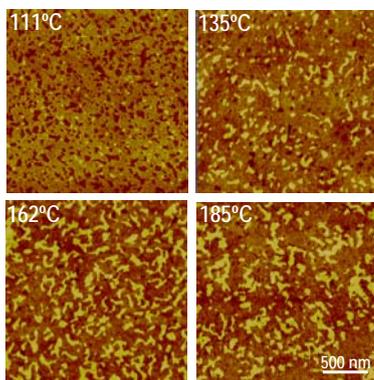
- Over 230 pBTTT-C<sub>12</sub> OFETs were processed simultaneously on a single substrate on the temperature gradient stage
- OFETs tested on automated Cascade probe station and were characterized in saturation and modeled by

$$I_D = \frac{WC_i}{2L} \mu (V_G - V_T)^2$$

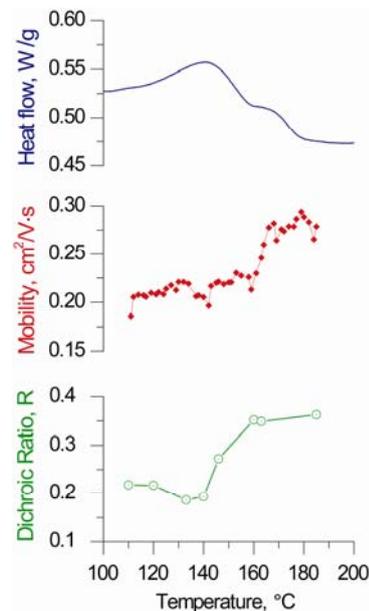
where  
 V<sub>D</sub> - drain voltage  
 V<sub>G</sub> - gate voltage  
 I<sub>D</sub> - drain current  
 L - channel length  
 W - channel width  
 C<sub>i</sub> - capacitance per dielectric unit area  
 V<sub>T</sub> - threshold voltage  
 μ - field-effect mobility



- Each pixel represents an individual transistor
- Mobility increases with temperature with transition region (160 to 165)°C
- Highest mobility ~ 0.3 cm<sup>2</sup>/V-s



- Atomic force microscopy (AFM) reveals formation of lamellar terraces (~2 nm height) during annealing
- As cast-films are featureless
- Step height corresponds to lamellar spacing
- Increased mobility coincides with heating into LC phase (DSC)
- Edge-on orientation of conjugated plane increases with temperature due to decrease in disorder of the film



# Summary

- Increase in carrier mobility coincides with heating pBTTT-C<sub>12</sub> into liquid crystalline phase as determined by DSC
- Mobility enhancement coincides with an increase in crystal domain size as observed by AFM and edge-on conjugated plane orientation as measured by NEXAFS
- Smooth correlation (temperature, structure) made possible by use of combinatorial temperature gradient
- This combinatorial method may find general utility for screening OFET performance
- This high-throughput approach can be used to optimize heat treatment, investigate materials with multiple phase transitions, or determine the lowest thermal budget required to increase performance
- Complete results published in Lucas, L. A. *et. al.*, Appl. Phys. Lett. 90, 012112, 2007

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